HIGH-SPEED 3.3V 128K x 36 SYNCHRONOUS BANK-SWITCHABLE DUAL-PORT STATIC RAM WITH 3.3V OR 2.5V INTERFACE

IDT70V7599S

Features:

♦ **128K x 36 Synchronous Bank-Switchable Dual-ported SRAM Architecture**
  – *64 independent 2K x 36 banks*
  – *4 megabits of memory on chip*
♦ **Bank access controlled via bank address pins**
♦ **High-speed data access**
  – *Commercial: 3.4ns (200MHz)/3.6ns (166MHz)/ 4.2ns (133MHz) (max.)*
  – *Industrial: 3.6ns (166MHz)/4.2ns (133MHz) (max.)*
♦ **Selectable Pipelined or Flow-Through output mode**
♦ **Counter enable and repeat features**
♦ **Dual chip enables allow for depth expansion without additional logic**
♦ **Full synchronous operation on both ports**
  – *5ns cycle time, 200MHz operation (14Gbps bandwidth)*
  – *Fast 3.4ns clock to data out*

  – *1.5ns setup to clock and 0.5ns hold on all control, data, and address inputs @ 200MHz*
  – *Data input, address, byte enable and control registers*
  – *Self-timed write allows fast cycle time*
♦ **Separate byte controls for multiplexed bus and bus matching compatibility**
♦ **LVTTL- compatible, 3.3V (±150mV) power supply for core**
♦ **LVTTL compatible, selectable 3.3V (±150mV) or 2.5V (±100mV) power supply for I/Os and control signals on each port**
♦ **Industrial temperature range (-40°C to +85°C) is available at 166MHz and 133MHz**
♦ **Available in a 208-pin Plastic Quad Flatpack (PQFP), 208-pin fine pitch Ball Grid Array (fpBGA), and 256-pin Ball Grid Array (BGA)**
♦ **Supports JTAG features compliant with IEEE 1149.1**

Functional Block Diagram

5626 drw 01
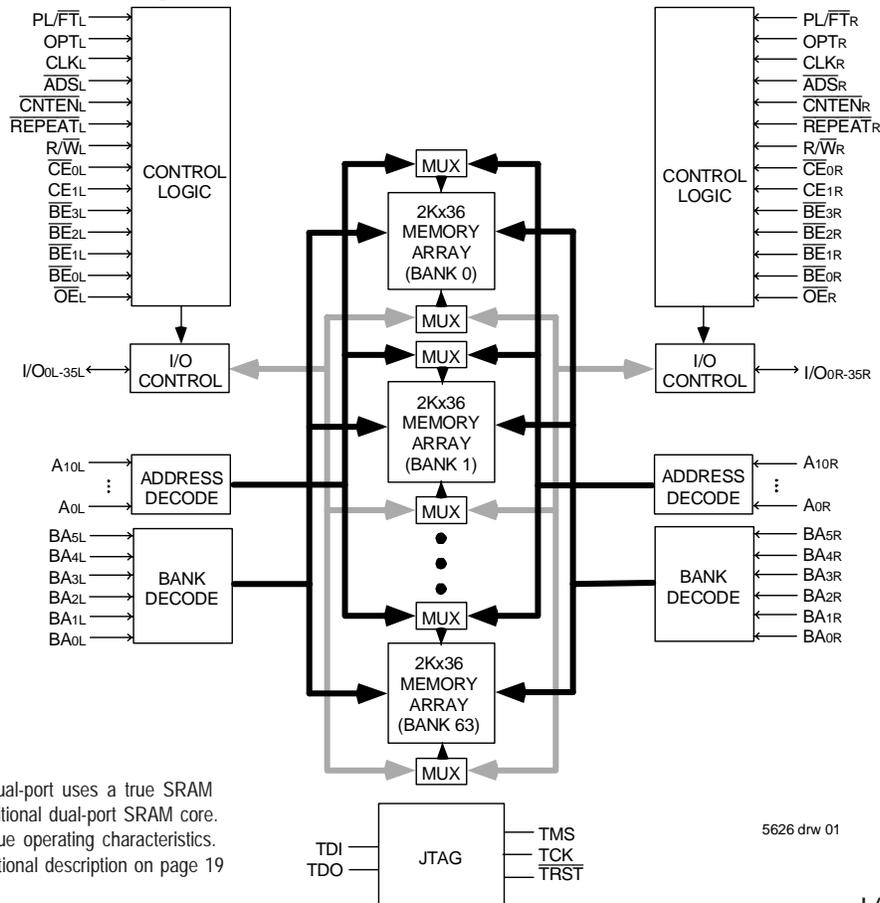
NOTE:
1. The Bank-Switchable dual-port uses a true SRAM core instead of the traditional dual-port SRAM core. As a result, it has unique operating characteristics. Please refer to the functional description on page 19 for details.

JANUARY 2009

DSC 5626/6

Description:

The IDT70V7599 is a high-speed 128Kx36 (4Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 2Kx36 banks. The device has two independent ports with separate control, address, and I/O pins for each port, allowing each port to access any 2Kx36 memory block not already accessed by the other port. Accesses by the ports into specific banks are controlled via the bank address pins under the user's direct control.

Registers on control, data, and address inputs provide minimal setup and hold times. The timing latitude provided by this approach allows systems to be designed with very short cycle times. With an input data register, the IDT70V7599 has been optimized for applications having unidirectional or bidirectional data flow in bursts. An automatic power down feature, controlled by $\overline{CE}_0$ and $\overline{CE}_1$, permits the on-chip circuitry of each port to enter a very low standby power mode. The dual chip enables also facilitate depth expansion.

The 70V7599 can support an operating voltage of either 3.3V or 2.5V on one or both ports, controllable by the OPT pins. The power supply for the core of the device(V_{DD}) remains at 3.3V. Please refer also to the functional description on page 19.

Pin Configuration[1,2,3,4]

11/08/01

1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17
A1 IO_{19L}	**A2** IO_{18L}	**A3** V_{SS}	**A4** TDO	**A5** NC	**A6** BA_{5L}	**A7** BA_{1L}	**A8** A_{8L}	**A9** $\overline{BE}_{1L}$	**A10** V_{DD}	**A11** CLK_L	**A12** $\overline{CNTEN}_L$	**A13** A_{4L}	**A14** A_{0L}	**A15** OPT_L	**A16** I/O_{17L}	**A17** V_{SS}
B1 I/O_{20R}	**B2** V_{SS}	**B3** I/O_{18R}	**B4** TDI	**B5** NC	**B6** BA_{2L}	**B7** A_{9L}	**B8** $\overline{BE}_{2L}$	**B9** $\overline{CE}_{0L}$	**B10** V_{SS}	**B11** $\overline{ADS}_L$	**B12** A_{5L}	**B13** A_{1L}	**B14** V_{SS}	**B15** V_{DDQR}	**B16** I/O_{16L}	**B17** I/O_{15R}
C1 V_{DDQL}	**C2** I/O_{19R}	**C3** V_{DDQR}	**C4** $PL/\overline{FT}_L$	**C5** NC	**C6** BA_{3L}	**C7** A_{10L}	**C8** $\overline{BE}_{3L}$	**C9** $\overline{CE}_{1L}$	**C10** V_{SS}	**C11** $R/\overline{W}_L$	**C12** A_{6L}	**C13** A_{2L}	**C14** V_{DD}	**C15** I/O_{16R}	**C16** I/O_{15L}	**C17** V_{SS}
D1 I/O_{22L}	**D2** V_{SS}	**D3** I/O_{21L}	**D4** I/O_{20L}	**D5** BA_{4L}	**D6** BA_{0L}	**D7** A_{7L}	**D8** $\overline{BE}_{0L}$	**D9** V_{DD}	**D10** $\overline{OE}_L$	**D11** $\overline{REPEAT}_L$	**D12** A_{3L}	**D13** V_{DD}	**D14** I/O_{17R}	**D15** V_{DDQL}	**D16** I/O_{14L}	**D17** I/O_{14R}
E1 I/O_{23L}	**E2** I/O_{22R}	**E3** V_{DDQL}	**E4** I/O_{21R}										**E14** I/O_{12L}	**E15** I/O_{13R}	**E16** V_{SS}	**E17** I/O_{13L}
F1 V_{DDQL}	**F2** I/O_{23R}	**F3** I/O_{24L}	**F4** V_{SS}										**F14** V_{SS}	**F15** I/O_{12R}	**F16** I/O_{11L}	**F17** V_{DDQR}
G1 I/O_{26L}	**G2** V_{SS}	**G3** I/O_{25L}	**G4** I/O_{24R}										**G14** I/O_{9L}	**G15** V_{DDQL}	**G16** I/O_{10L}	**G17** I/O_{11R}
H1 V_{DD}	**H2** I/O_{26R}	**H3** V_{DDQR}	**H4** I/O_{25R}										**H14** V_{DD}	**H15** IO_{9R}	**H16** V_{SS}	**H17** I/O_{10R}
J1 V_{DDQL}	**J2** V_{DD}	**J3** V_{SS}	**J4** V_{SS}										**J14** V_{SS}	**J15** V_{DD}	**J16** V_{SS}	**J17** V_{DDQR}
K1 I/O_{28R}	**K2** V_{SS}	**K3** I/O_{27R}	**K4** V_{SS}										**K14** I/O_{7R}	**K15** V_{DDQL}	**K16** I/O_{8R}	**K17** V_{SS}
L1 I/O_{29R}	**L2** I/O_{28L}	**L3** V_{DDQL}	**L4** I/O_{27L}										**L14** I/O_{6R}	**L15** I/O_{7L}	**L16** V_{SS}	**L17** I/O_{8L}
M1 V_{DDQL}	**M2** I/O_{29L}	**M3** I/O_{30L}	**M4** V_{SS}										**M14** V_{SS}	**M15** I/O_{6L}	**M16** I/O_{5R}	**M17** V_{DDQR}
N1 I/O_{31L}	**N2** V_{SS}	**N3** I/O_{31R}	**N4** I/O_{30L}										**N14** I/O_{3R}	**N15** V_{DDQL}	**N16** I/O_{4R}	**N17** I/O_{5L}
P1 I/O_{32R}	**P2** I/O_{32L}	**P3** V_{DDQR}	**P4** I/O_{35R}	**P5** $\overline{TRST}$	**P6** BA_{5R}	**P7** BA_{1R}	**P8** A_{8R}	**P9** $\overline{BE}_{1R}$	**P10** V_{DD}	**P11** CLK_R	**P12** $\overline{CNTEN}_R$	**P13** A_{4R}	**P14** I/O_{2L}	**P15** I/O_{3L}	**P16** V_{SS}	**P17** I/O_{4L}
R1 V_{SS}	**R2** I/O_{33L}	**R3** I/O_{34R}	**R4** TCK	**R5** NC	**R6** BA_{2R}	**R7** A_{9R}	**R8** $\overline{BE}_{2R}$	**R9** $\overline{CE}_{0R}$	**R10** V_{SS}	**R11** $\overline{ADS}_R$	**R12** A_{5R}	**R13** A_{1R}	**R14** V_{SS}	**R15** V_{DDQL}	**R16** I/O_{1R}	**R17** V_{DDQR}
T1 I/O_{33R}	**T2** I/O_{34L}	**T3** V_{DDQL}	**T4** TMS	**T5** NC	**T6** BA_{3R}	**T7** A_{10R}	**T8** $\overline{BE}_{3R}$	**T9** $\overline{CE}_{1R}$	**T10** V_{SS}	**T11** $R/\overline{W}_R$	**T12** A_{6R}	**T13** A_{2R}	**T14** V_{SS}	**T15** I/O_{0R}	**T16** V_{SS}	**T17** I/O_{2R}
U1 V_{SS}	**U2** I/O_{35L}	**U3** $PL/\overline{FT}_R$	**U4** NC	**U5** BA_{4R}	**U6** BA_{0R}	**U7** A_{7R}	**U8** $\overline{BE}_{0R}$	**U9** V_{DD}	**U10** $\overline{OE}_R$	**U11** $\overline{REPEAT}_R$	**U12** A_{3R}	**U13** A_{0R}	**U14** V_{DD}	**U15** OPT_R	**U16** I/O_{0L}	**U17** I/O_{1L}

Center of package:

70V7599BF
BF-208[5]

208-Pin fpBGA
Top View[6]

5626 drw 02c

NOTES:

1. All V_{DD} pins must be connected to 3.3V power supply.
2. All V_{DDQ} pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to V_{IH} (3.3V), and 2.5V if OPT pin for that port is set to V_{IL} (0V).
3. All V_{SS} pins must be connected to ground supply.
4. Package body is approximately 15mm x 15mm x 1.4mm with 0.8mm ball pitch.
5. This package code is used to reference the package diagram.
6. This text does not indicate orientation of the actual part-marking.

Pin Configuration[1,2,3,4] (con't.)

70V7599BC
BC-256[5]
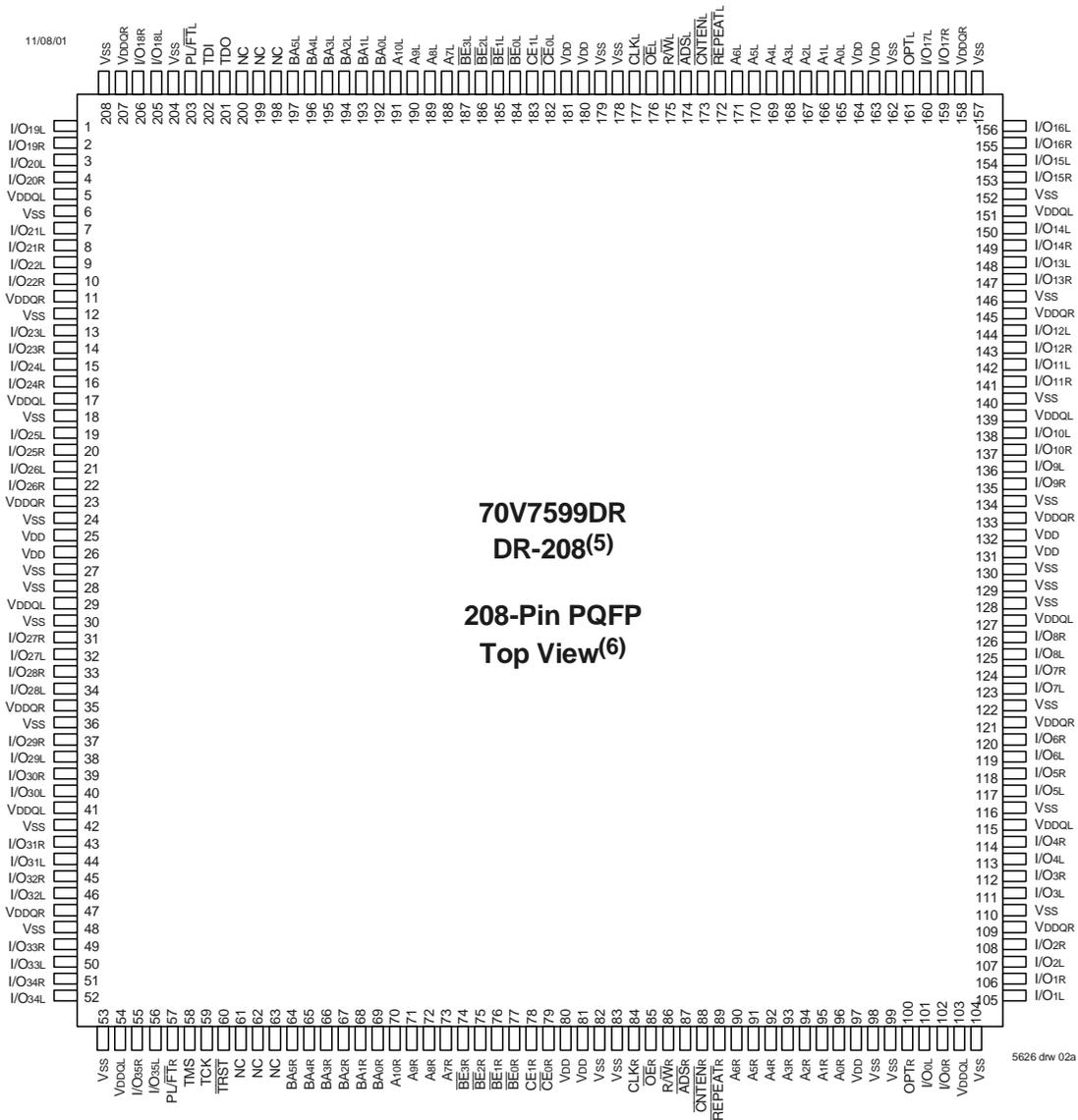
256-Pin BGA
Top View[6]

11/08/01

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
A	NC	TDI	NC	NC	BA_{3L}	BA_{0L}	A_{8L}	$\overline{BE}_{2L}$	CE_{1L}	$\overline{OE}_L$	$\overline{CNTEN}_L$	A_{5L}	A_{2L}	A_{0L}	NC	NC
B	I/O_{18L}	NC	TDO	NC	BA_{4L}	BA_{1L}	A_{9L}	$\overline{BE}_{3L}$	$\overline{CE}_{0L}$	$R/\overline{W}_L$	$\overline{REPEAT}_L$	A_{4L}	A_{1L}	V_{DD}	I/O_{17L}	NC
C	I/O_{18R}	I/O_{19L}	V_{SS}	BA_{5L}	BA_{2L}	A_{10L}	A_{7L}	$\overline{BE}_{1L}$	$\overline{BE}_{0L}$	CLK_L	$\overline{ADS}_L$	A_{6L}	A_{3L}	OPT_L	I/O_{17R}	I/O_{16L}
D	I/O_{20R}	I/O_{19R}	I/O_{20L}	$PL/\overline{FT}_L$	V_{DDQL}	V_{DDQL}	V_{DDQR}	V_{DDQR}	V_{DDQL}	V_{DDQL}	V_{DDQR}	V_{DDQR}	V_{DD}	I/O_{15R}	I/O_{15L}	I/O_{16R}
E	I/O_{21R}	I/O_{21L}	I/O_{22L}	V_{DDQL}	V_{DD}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DD}	V_{DDQR}	I/O_{13L}	I/O_{14L}	I/O_{14R}
F	I/O_{23L}	I/O_{22R}	I/O_{23R}	V_{DDQL}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQR}	I/O_{12R}	I/O_{13R}	I/O_{12L}
G	I/O_{24R}	I/O_{24L}	I/O_{25L}	V_{DDQR}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQL}	I/O_{10L}	I/O_{11L}	I/O_{11R}
H	I/O_{26L}	I/O_{25R}	I/O_{26R}	V_{DDQR}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQL}	I/O_{9R}	IO_{9L}	I/O_{10R}
J	I/O_{27L}	I/O_{28R}	I/O_{27R}	V_{DDQL}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQR}	I/O_{8R}	I/O_{7R}	I/O_{8L}
K	I/O_{29R}	I/O_{29L}	I/O_{28L}	V_{DDQL}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DDQR}	I/O_{6R}	I/O_{6L}	I/O_{7L}
L	I/O_{30L}	I/O_{31R}	I/O_{30R}	V_{DDQR}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DDQL}	I/O_{5L}	I/O_{4R}	I/O_{5R}
M	I/O_{32R}	I/O_{32L}	I/O_{31L}	V_{DDQR}	V_{DD}	V_{DD}	V_{SS}	V_{SS}	V_{SS}	V_{SS}	V_{DD}	V_{DD}	V_{DDQL}	I/O_{3R}	I/O_{3L}	I/O_{4L}
N	I/O_{33L}	I/O_{34R}	I/O_{33R}	$PL/\overline{FT}_R$	V_{DDQR}	V_{DDQR}	V_{DDQL}	V_{DDQL}	V_{DDQR}	V_{DDQR}	V_{DDQL}	V_{DDQL}	V_{DD}	I/O_{2L}	I/O_{1R}	I/O_{2R}
P	I/O_{35R}	I/O_{34L}	TMS	BA_{5R}	BA_{2R}	A_{10R}	A_{7R}	$\overline{BE}_{1R}$	$\overline{BE}_{0R}$	CLK_R	$\overline{ADS}_R$	A_{6R}	A_{3R}	I/O_{0L}	I/O_{0R}	I/O_{1L}
R	I/O_{35L}	NC	$\overline{TRST}$	NC	BA_{4R}	BA_{1R}	A_{9R}	$\overline{BE}_{3R}$	$\overline{CE}_{0R}$	$R/\overline{W}_R$	$\overline{REPEAT}_R$	A_{4R}	A_{1R}	OPT_R	NC	NC
T	NC	TCK	NC	NC	BA_{3R}	BA_{0R}	A_{8R}	$\overline{BE}_{2R}$	CE_{1R}	$\overline{OE}_R$	$\overline{CNTEN}_R$	A_{5R}	A_{2R}	A_{0R}	NC	NC

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NOTES:
1. All V_{DD} pins must be connected to 3.3V power supply.
2. All V_{DDQ} pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to V_{IH} (3.3V), and 2.5V if OPT pin for that port is set to V_{IL} (0V).
3. All V_{SS} pins must be connected to ground supply.
4. Package body is approximately 17mm x 17mm x 1.4mm, with 1.0mm ball-pitch.
5. This package code is used to reference the package diagram.
6. This text does not indicate orientation of the actual part-marking.

Pin Configuration[1,2,3,4] (con't.)

11/08/01

Top edge pins (208–157):

Pin	Signal	Pin	Signal	Pin	Signal	Pin	Signal
208	VSS	207	VDDQR	206	I/O18R	205	I/O18L
204	VSS	203	PL/FTL	202	TDI	201	TDO
200	NC	199	NC	198	NC	197	BA5L
196	BA4L	195	BA3L	194	BA2L	193	BA1L
192	BA0L	191	A10L	190	A9L	189	A8L
188	A7L	187	$\overline{BE3L}$	186	$\overline{BE2L}$	185	$\overline{BE1L}$
184	$\overline{BE0L}$	183	$\overline{CE1L}$	182	$\overline{CE0L}$	181	VDD
180	VDD	179	VSS	178	VSS	177	CLKL
176	$\overline{OEL}$	175	R/WL	174	$\overline{ADSL}$	173	$\overline{CNTENL}$
172	REPEATL	171	A6L	170	A5L	169	A4L
168	A3L	167	A2L	166	A1L	165	A0L
164	VDD	163	VSS	162	VSS	161	OPTL
160	I/O17L	159	I/O17R	158	VDDQR	157	VSS

Left edge pins (1–52):

Pin	Signal
1	I/O19L
2	I/O19R
3	I/O20L
4	I/O20R
5	VDDQL
6	VSS
7	I/O21L
8	I/O21R
9	I/O22L
10	I/O22R
11	VDDQR
12	VSS
13	I/O23L
14	I/O23R
15	I/O24L
16	I/O24R
17	VDDQL
18	VSS
19	I/O25L
20	I/O25R
21	I/O26L
22	I/O26R
23	VDDQR
24	VSS
25	VDD
26	VDD
27	VSS
28	VSS
29	VDDQL
30	VSS
31	I/O27R
32	I/O27L
33	I/O28R
34	I/O28L
35	VDDQR
36	VSS
37	I/O29R
38	I/O29L
39	I/O30R
40	I/O30L
41	VDDQL
42	VSS
43	I/O31R
44	I/O31L
45	I/O32R
46	I/O32L
47	VDDQR
48	VSS
49	I/O33R
50	I/O33L
51	I/O34R
52	I/O34L

Center label:

70V7599DR
DR-208[5]

208-Pin PQFP
Top View[6]

Right edge pins (156–105):

Pin	Signal
156	I/O16L
155	I/O16R
154	I/O15L
153	I/O15R
152	VSS
151	VDDQL
150	I/O14L
149	I/O14R
148	I/O13L
147	I/O13R
146	VSS
145	VDDQR
144	I/O12L
143	I/O12R
142	I/O11L
141	I/O11R
140	VSS
139	VDDQL
138	I/O10L
137	I/O10R
136	I/O9L
135	I/O9R
134	VSS
133	VDDQR
132	VDD
131	VDD
130	VSS
129	VSS
128	VDDQL
127	I/O8R
126	I/O8L
125	I/O7R
124	I/O7L
123	VSS
122	VDDQR
121	I/O6R
120	I/O6L
119	I/O5R
118	I/O5L
117	VSS
116	VDDQL
115	I/O4R
114	I/O4L
113	I/O3R
112	I/O3L
111	VSS
110	VDDQR
109	I/O2R
108	I/O2L
107	I/O1R
106	I/O1L
105	I/O1L

Bottom edge pins (53–104):

Pin	Signal	Pin	Signal
53	VSS	54	VDDQL
55	I/O35R	56	I/O35L
57	PL/FTr	58	TMS
59	TCK	60	$\overline{TRST}$
61	NC	62	NC
63	NC	64	BA5R
65	BA4R	66	BA3R
67	BA2R	68	BA1R
69	BA0R	70	A10R
71	A9R	72	A8R
73	A7R	74	$\overline{BE3R}$
75	$\overline{BE2R}$	76	$\overline{BE1R}$
77	$\overline{BE0R}$	78	$\overline{CE1R}$
79	$\overline{CE0R}$	80	VDD
81	VDD	82	VSS
83	VSS	84	CLKr
85	$\overline{OEr}$	86	R/Wr
87	$\overline{ADSr}$	88	$\overline{CNTENr}$
89	REPEATr	90	A6R
91	A5R	92	A4R
93	A3R	94	A2R
95	A1R	96	A0R
97	VDD	98	VSS
99	VSS	100	OPTr
101	I/O0L	102	I/O0R
103	VDDQL	104	VSS

5626 drw 02a

NOTES:
1. All VDD pins must be connected to 3.3V power supply.
2. All VDDQ pins must be connected to appropriate power supply: 3.3V if OPT pin for that port is set to VIH (3.3V), and 2.5V if OPT pin for that port is set to VIL (0V).
3. All VSS pins must be connected to ground supply.
4. Package body is approximately 28mm x 28mm x 3.5mm.
5. This package code is used to reference the package diagram.
6. This text does not indicate orientation of the actual part-marking.

Pin Names

Left Port	Right Port	Names
$\overline{CE}_{0L}$, CE_{1L}	$\overline{CE}_{0R}$, CE_{1R}	Chip Enables
$R/\overline{W}_L$	$R/\overline{W}_R$	Read/Write Enable
$\overline{OE}_L$	$\overline{OE}_R$	Output Enable
BA_{0L} - BA_{5L}	BA_{0R} - BA_{5R}	Bank Address[4]
A_{0L} - A_{10L}	A_{0R} - A_{10R}	Address
I/O_{0L} - I/O_{35L}	I/O_{0R} - I/O_{35R}	Data Input/Output
CLK_L	CLK_R	Clock
$PL/\overline{FT}_L$	$PL/\overline{FT}_R$	Pipeline/Flow-Through
$\overline{ADS}_L$	$\overline{ADS}_R$	Address Strobe Enable
$\overline{CNTEN}_L$	$\overline{CNTEN}_R$	Counter Enable
$\overline{REPEAT}_L$	$\overline{REPEAT}_R$	Counter Repeat[3]
$\overline{BE}_{0L}$ - $\overline{BE}_{3L}$	$\overline{BE}_{0R}$ - $\overline{BE}_{3R}$	Byte Enables (9-bit bytes)
V_{DDQL}	V_{DDQR}	Power (I/O Bus) (3.3V or 2.5V)[1]
OPT_L	OPT_R	Option for selecting V_{DDQX}[1,2]
V_{DD}		Power (3.3V)[1]
V_{SS}		Ground (0V)
TDI		Test Data Input
TDO		Test Data Output
TCK		Test Logic Clock (10MHz)
TMS		Test Mode Select
$\overline{TRST}$		Reset (Initialize TAP Controller)

5626 tbl 01

NOTES:
1. V_{DD}, OPT_X, and V_{DDQX} must be set to appropriate operating levels prior to applying inputs on the I/Os and controls for that port.
2. OPT_X selects the operating voltage levels for the I/Os and controls on that port. If OPT_X is set to VIH (3.3V), then that port's I/Os and controls will operate at 3.3V levels and V_{DDQX} must be supplied at 3.3V. If OPT_X is set to VIL (0V), then that port's I/Os and address controls will operate at 2.5V levels and V_{DDQX} must be supplied at 2.5V. The OPT pins are independent of one another—both ports can operate at 3.3V levels, both can operate at 2.5V levels, or either can operate at 3.3V with the other at 2.5V.
3. When $\overline{REPEAT}_X$ is asserted, the counter will reset to the last valid address loaded via $\overline{ADS}_X$.
4. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e., BA_{0L} - $BA_{5L} \neq BA_{0R}$ - BA_{5R}). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).

Truth Table I—Read/Write and Enable Control[1,2,3,4]

$\overline{OE}$[3]	CLK	$\overline{CE}_0$	CE_1	$\overline{BE}_3$	$\overline{BE}_2$	$\overline{BE}_1$	$\overline{BE}_0$	R/$\overline{W}$	Byte 3 I/O27-35	Byte 2 I/O18-26	Byte 1 I/O9-17	Byte 0 I/O0-8	MODE
X	↑	H	X	X	X	X	X	X	High-Z	High-Z	High-Z	High-Z	Deselected–Power Down
X	↑	X	L	X	X	X	X	X	High-Z	High-Z	High-Z	High-Z	Deselected–Power Down
X	↑	L	H	H	H	H	H	X	High-Z	High-Z	High-Z	High-Z	All Bytes Deselected
X	↑	L	H	H	H	H	L	L	High-Z	High-Z	High-Z	D$_{IN}$	Write to Byte 0 Only
X	↑	L	H	H	H	L	H	L	High-Z	High-Z	D$_{IN}$	High-Z	Write to Byte 1 Only
X	↑	L	H	H	L	H	H	L	High-Z	D$_{IN}$	High-Z	High-Z	Write to Byte 2 Only
X	↑	L	H	L	H	H	H	L	D$_{IN}$	High-Z	High-Z	High-Z	Write to Byte 3 Only
X	↑	L	H	H	H	L	L	L	High-Z	High-Z	D$_{IN}$	D$_{IN}$	Write to Lower 2 Bytes Only
X	↑	L	H	L	L	H	H	L	D$_{IN}$	D$_{IN}$	High-Z	High-Z	Write to Upper 2 bytes Only
X	↑	L	H	L	L	L	L	L	D$_{IN}$	D$_{IN}$	D$_{IN}$	D$_{IN}$	Write to All Bytes
L	↑	L	H	H	H	H	L	H	High-Z	High-Z	High-Z	D$_{OUT}$	Read Byte 0 Only
L	↑	L	H	H	H	L	H	H	High-Z	High-Z	D$_{OUT}$	High-Z	Read Byte 1 Only
L	↑	L	H	H	L	H	H	H	High-Z	D$_{OUT}$	High-Z	High-Z	Read Byte 2 Only
L	↑	L	H	L	H	H	H	H	D$_{OUT}$	High-Z	High-Z	High-Z	Read Byte 3 Only
L	↑	L	H	H	H	L	L	H	High-Z	High-Z	D$_{OUT}$	D$_{OUT}$	Read Lower 2 Bytes Only
L	↑	L	H	L	L	H	H	H	D$_{OUT}$	D$_{OUT}$	High-Z	High-Z	Read Upper 2 Bytes Only
L	↑	L	H	L	L	L	L	H	D$_{OUT}$	D$_{OUT}$	D$_{OUT}$	D$_{OUT}$	Read All Bytes
H	X	X	X	X	X	X	X	X	High-Z	High-Z	High-Z	High-Z	Outputs Disabled

5626 tbl 02

NOTES:
1. "H" = V$_{IH}$, "L" = V$_{IL}$, "X" = Don't Care.
2. $\overline{ADS}$, $\overline{CNTEN}$, $\overline{REPEAT}$ are set as appropriate for address access. Refers to Truth Table II for details.
3. $\overline{OE}$ is an asynchronous input signal.
4. It is possible to read or write any combination of bytes during a given access. A few representative samples have been illustrated here.

Truth Table II—Address and Address Counter Control[1,2,7]

Address	Previous Address	Addr Used	CLK	$\overline{ADS}$	$\overline{CNTEN}$	$\overline{REPEAT}$[6]	I/O[3]	MODE
An	X	An	↑	L[4]	X	H	D$_{I/O}$ (n)	External Address Used
X	An	An + 1	↑	H	L[5]	H	D$_{I/O}$(n+1)	Counter Enabled—Internal Address generation
X	An + 1	An + 1	↑	H	H	H	D$_{I/O}$(n+1)	External Address Blocked—Counter disabled (An + 1 reused)
X	X	An	↑	X	X	L[4]	D$_{I/O}$(0)	Counter Set to last valid $\overline{ADS}$ load

5626 tbl 03

NOTES:
1. "H" = V$_{IH}$, "L" = V$_{IL}$, "X" = Don't Care.
2. Read and write operations are controlled by the appropriate setting of R/$\overline{W}$, $\overline{CE}_0$, CE_1, $\overline{BE}n$ and $\overline{OE}$.
3. Outputs configured in flow-through output mode: if outputs are in pipelined mode the data out will be delayed by one cycle.
4. $\overline{ADS}$ and $\overline{REPEAT}$ are independent of all other memory control signals including $\overline{CE}_0$, CE_1 and $\overline{BE}n$
5. The address counter advances if $\overline{CNTEN}$ = V$_{IL}$ on the rising edge of CLK, regardless of all other memory control signals including $\overline{CE}_0$, CE_1, $\overline{BE}n$.
6. When $\overline{REPEAT}$ is asserted, the counter will reset to the last valid address loaded via $\overline{ADS}$. This value is not set at power-up: a known location should be loaded via $\overline{ADS}$ during initialization if desired. Any subsequent $\overline{ADS}$ access during operations will update the $\overline{REPEAT}$ address location.
7. The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0. Refer to Timing Waveform of Counter Repeat, page 18. Care should be taken during operation to avoid having both counters point to the same bank (i.e., ensure BA$_{0L}$ - BA$_{5L}$ ≠ BA$_{0R}$ - BA$_{5R}$), as this condition will invalidate the access for both ports. Please refer to the functional description on page 19 for details.

Recommended Operating Temperature and Supply Voltage[1]

Grade	Ambient Temperature	GND	V_{DD}
Commercial	0°C to +70°C	0V	3.3V ± 150mV
Industrial	-40°C to +85°C	0V	3.3V ± 150mV

5626 tbl 04

NOTE:
1. This is the parameter T_A. This is the "instant on" case temperature.

Absolute Maximum Ratings[1]

Symbol	Rating	Commercial & Industrial	Unit
V_{TERM}[2]	Terminal Voltage with Respect to GND	-0.5 to +4.6	V
T_{BIAS}	Temperature Under Bias	-55 to +125	°C
T_{STG}	Storage Temperature	-65 to +150	°C
I_{OUT}	DC Output Current	50	mA

5626 tbl 06

NOTES:
1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
2. V_{TERM} must not exceed V_{DD} + 150mV for more than 25% of the cycle time or 4ns maximum, and is limited to $\leq$ 20mA for the period of $V_{TERM} \geq V_{DD}$ + 150mV.

Recommended DC Operating Conditions with V_{DDQ} at 2.5V

Symbol	Parameter	Min.	Typ.	Max.	Unit
V_{DD}	Core Supply Voltage	3.15	3.3	3.45	V
V_{DDQ}	I/O Supply Voltage[3]	2.4	2.5	2.6	V
V_{SS}	Ground	0	0	0	V
V_{IH}	Input High Voltage (Address & Control Inputs)	1.7	—	V_{DDQ} + 100mV[2]	V
V_{IH}	Input High Voltage - I/O[3]	1.7	—	V_{DDQ} + 100mV[2]	V
V_{IL}	Input Low Voltage	-0.3[1]	—	0.7	V

5626 tbl 05a

NOTES:
1. Undershoot of $V_{IL} \geq$ -1.5V for pulse width less than 10ns is allowed.
2. V_{TERM} must not exceed V_{DDQ} + 100mV.
3. To select operation at 2.5V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to V_{IL} (0V), and V_{DDQX} for that port must be supplied as indicated above.

Recommended DC Operating Conditions with V_{DDQ} at 3.3V

Symbol	Parameter	Min.	Typ.	Max.	Unit
V_{DD}	Core Supply Voltage	3.15	3.3	3.45	V
V_{DDQ}	I/O Supply Voltage[3]	3.15	3.3	3.45	V
V_{SS}	Ground	0	0	0	V
V_{IH}	Input High Voltage (Address & Control Inputs)[3]	2.0	—	V_{DDQ} + 150mV[2]	V
V_{IH}	Input High Voltage - I/O[3]	2.0	—	V_{DDQ} + 150mV[2]	V
V_{IL}	Input Low Voltage	-0.3[1]	—	0.8	V

5626 tbl 05b

NOTES:
1. Undershoot of $V_{IL} \geq$ -1.5V for pulse width less than 10ns is allowed.
2. V_{TERM} must not exceed V_{DDQ} + 150mV.
3. To select operation at 3.3V levels on the I/Os and controls of a given port, the OPT pin for that port must be set to V_{IH} (3.3V), and V_{DDQX} for that port must be supplied as indicated above.

Capacitance[1]

(T$_A$ = +25°C, F = 1.0MHz) PQFP ONLY

Symbol	Parameter	Conditions[2]	Max.	Unit
C$_{IN}$	Input Capacitance	V$_{IN}$ = 3dV	8	pF
C$_{OUT}$[3]	Output Capacitance	V$_{OUT}$ = 3dV	10.5	pF

5626 tbl 07

NOTES:
1. These parameters are determined by device characterization, but are not production tested.
2. 3dV references the interpolated capacitance when the input and output switch from 0V to 3V or from 3V to 0V.
3. C$_{OUT}$ also references C$_{I/O}$.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range (V$_{DD}$ = 3.3V ± 150mV)

Symbol	Parameter	Test Conditions	70V7599S Min.	70V7599S Max.	Unit
|I$_{LI}$|	Input Leakage Current[1]	V$_{DDQ}$ = Max., V$_{IN}$ = 0V to V$_{DDQ}$	—	10	μA
|I$_{LO}$|	Output Leakage Current[1]	$\overline{CE}$0 = V$_{IH}$ or CE1 = V$_{IL}$, V$_{OUT}$ = 0V to V$_{DDQ}$	—	10	μA
V$_{OL}$ (3.3V)	Output Low Voltage[2]	I$_{OL}$ = +4mA, V$_{DDQ}$ = Min.	—	0.4	V
V$_{OH}$ (3.3V)	Output High Voltage[2]	I$_{OH}$ = -4mA, V$_{DDQ}$ = Min.	2.4	—	V
V$_{OL}$ (2.5V)	Output Low Voltage[2]	I$_{OL}$ = +2mA, V$_{DDQ}$ = Min.	—	0.4	V
V$_{OH}$ (2.5V)	Output High Voltage[2]	I$_{OH}$ = -2mA, V$_{DDQ}$ = Min.	2.0	—	V

5626 tbl 08

NOTES:
1. At V$_{DD}$ $\leq$ 2.0V leakages are undefined.
2. V$_{DDQ}$ is selectable (3.3V/2.5V) via OPT pins. Refer to p.5 for details.

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range[5] (V_{DD} = 3.3V ± 150mV)

Symbol	Parameter	Test Condition	Version		70V7599S200[7] Com'l Only		70V7599S166[6] Com'l & Ind		70V7599S133 Com'l & Ind		Unit
					Typ.[4]	Max.	Typ.[4]	Max.	Typ.[4]	Max.	
I_{DD}	Dynamic Operating Current (Both Ports Active)	$\overline{CE}_L$ and $\overline{CE}_R$= V_{IL}, Outputs Disabled, f = f_{MAX}[1]	COM'L	S	815	950	675	790	550	645	mA
			IND	S	—	—	675	830	550	675	
I_{SB1}	Standby Current (Both Ports - TTL Level Inputs)	$\overline{CE}_L$ = $\overline{CE}_R$ = V_{IH} f = f_{MAX}[1]	COM'L	S	340	410	275	340	250	295	mA
			IND	S	—	—	275	355	250	310	
I_{SB2}	Standby Current (One Port - TTL Level Inputs)	$\overline{CE}$"A" = V_{IL} and $\overline{CE}$"B" = V_{IH}[3] Active Port Outputs Disabled, f=f_{MAX}[1]	COM'L	S	690	770	515	640	460	520	mA
			IND	S	—	—	515	660	460	545	
I_{SB3}	Full Standby Current (Both Ports - CMOS Level Inputs)	Both Ports $\overline{CE}_L$ and $\overline{CE}_R \geq V_{DDQ}$ - 0.2V, $V_{IN} \geq V_{DDQ}$ - 0.2V or $V_{IN} \leq$ 0.2V, f = 0[2]	COM'L	S	10	30	10	30	10	30	mA
			IND	S	—	—	10	40	10	40	
I_{SB4}	Full Standby Current (One Port - CMOS Level Inputs)	$\overline{CE}$"A" $\leq$ 0.2V and $\overline{CE}$"B" $\geq V_{DDQ}$ - 0.2V[5] $V_{IN} \geq V_{DDQ}$ - 0.2V or $V_{IN} \leq$ 0.2V, Active Port, Outputs Disabled, f = f_{MAX}[1]	COM'L	S	690	770	515	640	460	520	mA
			IND	S	—	—	515	660	460	545	

5626 tbl 09

NOTES:
1. At f = f_{MAX}, address and control lines (except Output Enable) are cycling at the maximum frequency clock cycle of 1/t_{CYC}, using "AC TEST CONDITIONS" at input levels of GND to 3V.
2. f = 0 means no address, clock, or control lines change. Applies only to input at CMOS level standby.
3. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
4. V_{DD} = 3.3V, T_A = 25°C for Typ, and are not production tested. I_{DD} DC(f=0) = 120mA (Typ).
5. $\overline{CE}$x = V_{IL} means $\overline{CE}$0x = V_{IL} and CE1x = V_{IH}
   $\overline{CE}$x = V_{IH} means $\overline{CE}$0x = V_{IH} or CE1x = V_{IL}
   $\overline{CE}$x $\leq$ 0.2V means $\overline{CE}$0x $\leq$ 0.2V and CE1x $\geq V_{DDQ}$ - 0.2V
   $\overline{CE}$x $\geq V_{DDQ}$ - 0.2V means $\overline{CE}$0x $\geq V_{DDQ}$ - 0.2V or CE1x $\leq$ 0.2V
   "X" represents "L" for left port or "R" for right port.
6. 166MHz Industrial Temperature not available in BF-208 package.
7. This speed grade available when V_{DDQ} = 3.3.V for a specific port (i.e., OPTx = V_{IH}). This speed grade available in BC-256 package only.

AC Test Conditions (V$_{DDQ}$ - 3.3V/2.5V)

Input Pulse Levels (Address & Controls)	GND to 3.0V/GND to 2.4V
Input Pulse Levels (I/Os)	GND to 3.0V/GND to 2.4V
Input Rise/Fall Times	2ns
Input Timing Reference Levels	1.5V/1.25V
Output Reference Levels	1.5V/1.25V
Output Load	Figures 1 and 2

5626 tbl 10
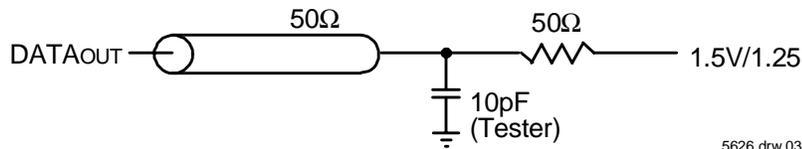
Figure 1. AC Output Test load.
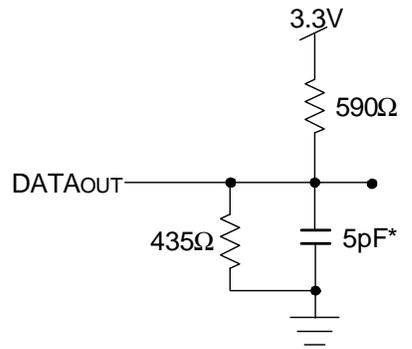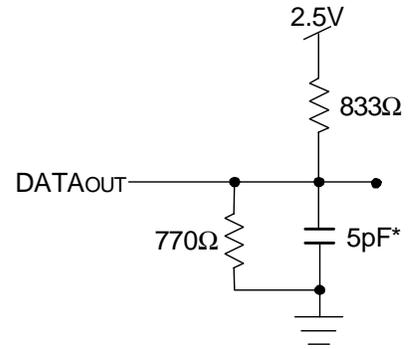
Figure 2. Output Test Load
(For t$_{CKLZ}$, t$_{CKHZ}$, t$_{OLZ}$, and t$_{OHZ}$).
*Including scope and jig.

10.5pF is the I/O capacitance of this device, and 10pF is the AC Test Load Capacitance.
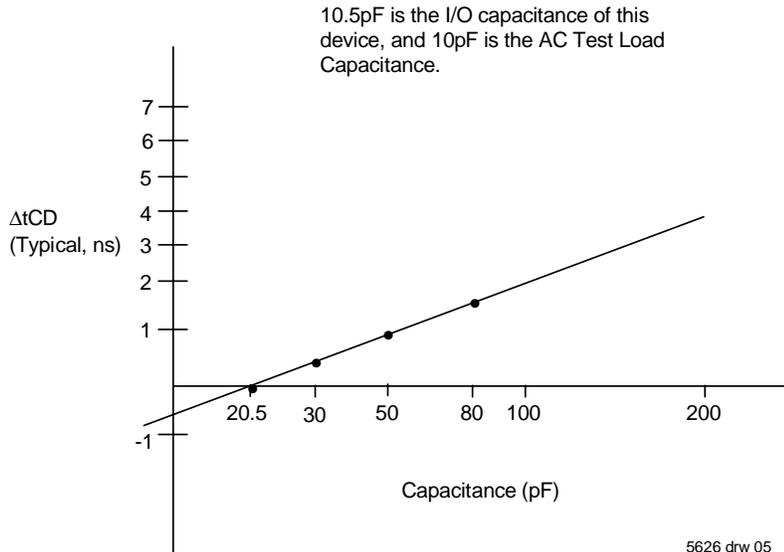
5626 drw 05

Figure 3. Typical Output Derating (Lumped Capacitive Load).

AC Electrical Characteristics Over the Operating Temperature Range (Read and Write Cycle Timing)[2] (V_{DD} = 3.3V ± 150mV, T_A = 0°C to +70°C)

Symbol	Parameter	70V7599S200[5] Com'l Only Min.	Max.	70V7599S166[3,4] Com'l & Ind Min.	Max.	70V7599S133[3] Com'l & Ind Min.	Max.	Unit
t_{CYC1}	Clock Cycle Time (Flow-Through)[1]	15	—	20	—	25	—	ns
t_{CYC2}	Clock Cycle Time (Pipelined)[1]	5	—	6	—	7.5	—	ns
t_{CH1}	Clock High Time (Flow-Through)[1]	5	—	6	—	7	—	ns
t_{CL1}	Clock Low Time (Flow-Through)[1]	5	—	6	—	7	—	ns
t_{CH2}	Clock High Time (Pipelined)[2]	2.0	—	2.1	—	2.6	—	ns
t_{CL2}	Clock Low Time (Pipelined)[1]	2.0	—	2.1	—	2.6	—	ns
t_R	Clock Rise Time	—	1.5	—	1.5	—	1.5	ns
t_F	Clock Fall Time	—	1.5	—	1.5	—	1.5	ns
t_{SA}	Address Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HA}	Address Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SC}	Chip Enable Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HC}	Chip Enable Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SB}	Byte Enable Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HB}	Byte Enable Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SW}	R/W Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HW}	R/W Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SD}	Input Data Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HD}	Input Data Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SAD}	$\overline{ADS}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HAD}	$\overline{ADS}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SCN}	$\overline{CNTEN}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HCN}	$\overline{CNTEN}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{SRPT}	$\overline{REPEAT}$ Setup Time	1.5	—	1.7	—	1.8	—	ns
t_{HRPT}	$\overline{REPEAT}$ Hold Time	0.5	—	0.5	—	0.5	—	ns
t_{OE}	Output Enable to Data Valid	—	4.0	—	4.0	—	4.2	ns
t_{OLZ}	Output Enable to Output Low-Z	0.5	—	0.5	—	0.5	—	ns
t_{OHZ}	Output Enable to Output High-Z	1	3.4	1	3.6	1	4.2	ns
t_{CD1}	Clock to Data Valid (Flow-Through)[1]	—	10	—	12	—	15	ns
t_{CD2}	Clock to Data Valid (Pipelined)[1]	—	3.4	—	3.6	—	4.2	ns
t_{DC}	Data Output Hold After Clock High	1	—	1	—	1	—	ns
t_{CKHZ}	Clock High to Output High-Z	1	3.4	1	3.6	1	4.2	ns
t_{CKLZ}	Clock High to Output Low-Z	0.5	—	0.5	—	0.5	—	ns
Port-to-Port Delay								
t_{CO}	Clock-to-Clock Offset	5.0	—	6.0	—	7.5	—	ns

5626 tbl 11

NOTES:
1. The Pipelined output parameters (t_{CYC2}, t_{CD2}) apply to either or both left and right ports when $\overline{FT}$/PIPEx = V_{IH}. Flow-through parameters (t_{CYC1}, t_{CD1}) apply when $\overline{FT}$/PIPEx = V_{IL} for that port.
2. All input signals are synchronous with respect to the clock except for the asynchronous Output Enable ($\overline{OE}$) and $\overline{FT}$/PIPE. $\overline{FT}$/PIPE should be treated as a DC signal, i.e. steady state during operation.
3. These values are valid for either level of V_{DDQ} (3.3V/2.5V). See page 5 for details on selecting the desired operating voltage levels for each port.
4. 166MHz Industrial Temperature not available in BF-208 package.
5. This speed grade available when V_{DDQ} = 3.3.V for a specific port (i.e., OPTx = V_{IH}). This speed grade available in BC-256 package only.

Timing Waveform of Read Cycle for Pipelined Operation ($\overline{ADS}$ Operation) ($\overline{FT}$/PIPE'x' = V_{IH})[2]
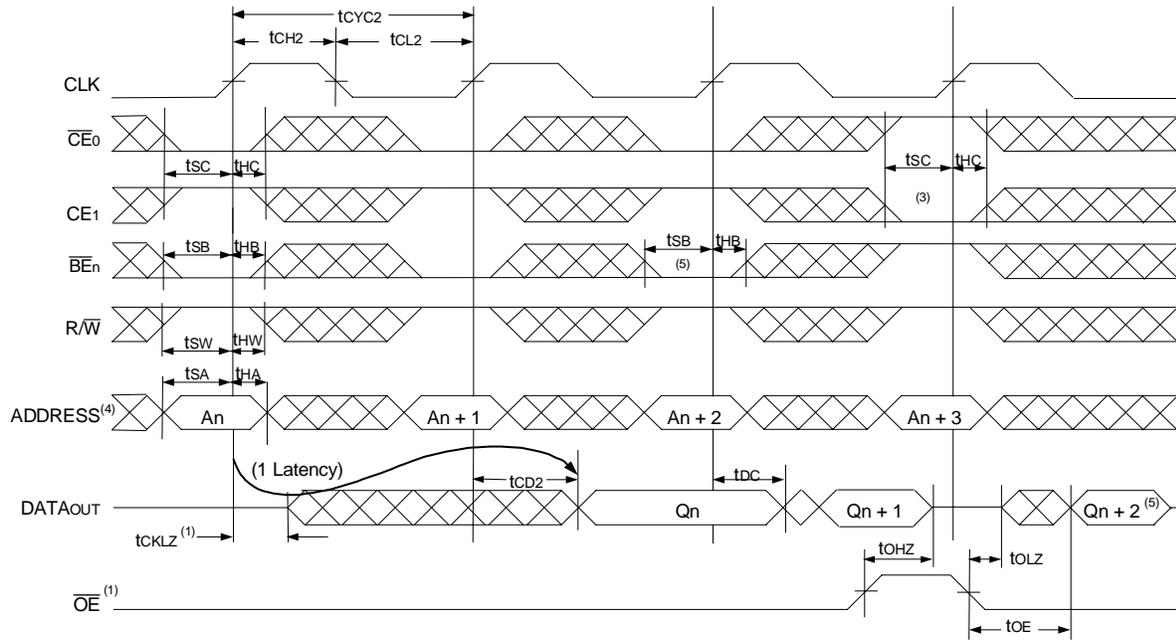
5626 drw 06

Timing Waveform of Read Cycle for Flow-through Output ($\overline{FT}$/PIPE"x" = V_{IL})[2,6]
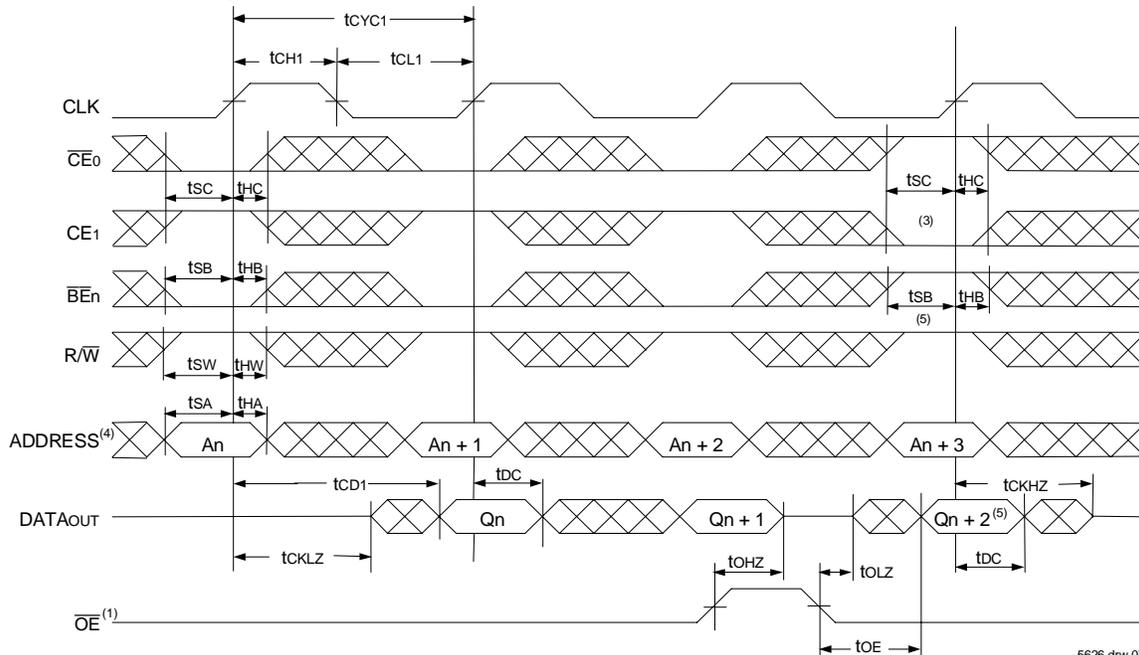
5626 drw 07

NOTES:
1. $\overline{OE}$ is asynchronously controlled; all other inputs are synchronous to the rising clock edge.
2. $\overline{ADS}$ = V_{IL}, $\overline{CNTEN}$ and $\overline{REPEAT}$ = V_{IH}.
3. The output is disabled (High-Impedance state) by $\overline{CE_0}$ = V_{IH}, CE1 = V_{IL}, $\overline{BE}_n$ = V_{IH} following the next rising edge of the clock. Refer to Truth Table 1.
4. Addresses do not have to be accessed sequentially since $\overline{ADS}$ = V_{IL} constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
5. If $\overline{BE}_n$ was HIGH, then the appropriate Byte of DATAOUT for Qn + 2 would be disabled (High-Impedance state).
6. "x" denotes Left or Right port. The diagram is with respect to that port.

Timing Waveform of a Multi-Device Pipelined Read[1,2]
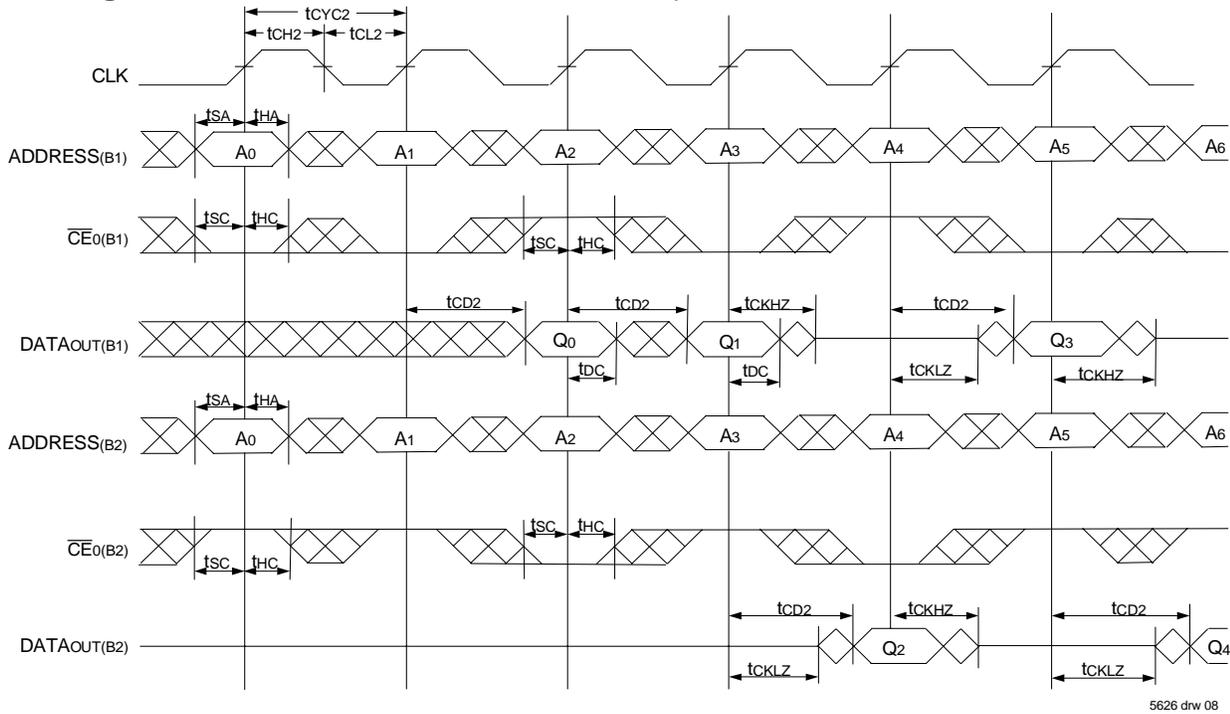
5626 drw 08

Timing Waveform of a Multi-Device Flow-Through Read[1,2]
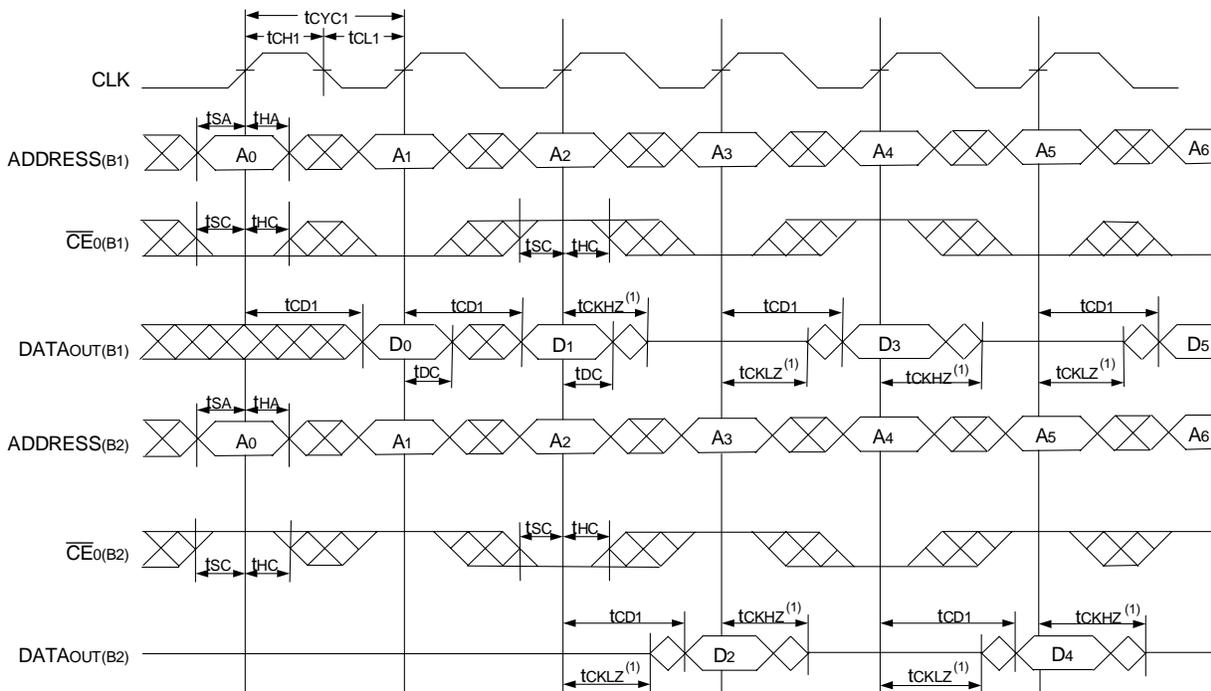
5626 drw 09

NOTES:
1. B1 Represents Device #1; B2 Represents Device #2. Each Device consists of one IDT70V7599 for this waveform, and are setup for depth expansion in this example. ADDRESS(B1) = ADDRESS(B2) in this situation.
2. $\overline{BE}_n$, $\overline{OE}$, and $\overline{ADS}$ = V_{IL}; CE1(B1), CE1(B2), $R/\overline{W}$, $\overline{CNTEN}$, and $\overline{REPEAT}$ = V_{IH}.

Timing Waveform of Port A Write to Pipelined Port B Read[1,2,4]

5626 drw 10
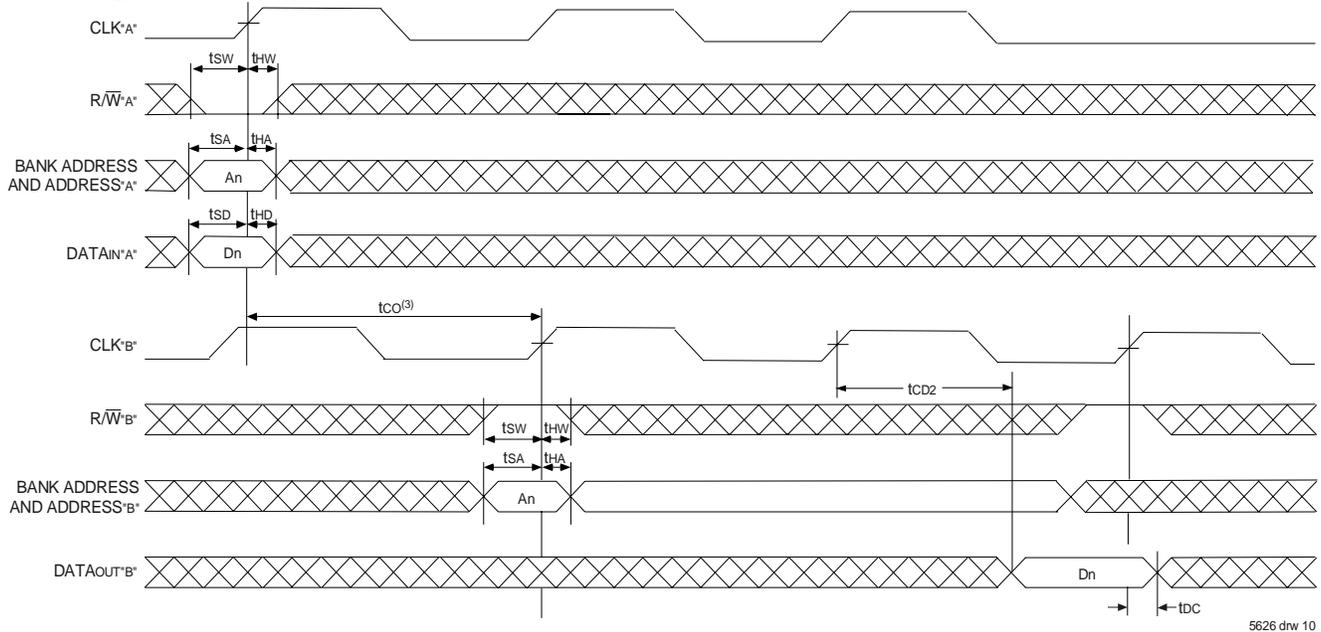
NOTES:
1. $\overline{CE}_0$, $\overline{BE}_n$, and $\overline{ADS}$ = V_{IL}; CE1, $\overline{CNTEN}$, and $\overline{REPEAT}$ = V_{IH}.
2. $\overline{OE}$ = V_{IL} for Port "B", which is being read from. $\overline{OE}$ = V_{IH} for Port "A", which is being written to.
3. If t_{CO} < minimum specified, then operations from both ports are INVALID. If $t_{CO} \geq$ minimum, then data from Port "B" read is available on first Port "B" clock cycle (ie, time from write to valid read on opposite port will be $t_{CO} + t_{CYC2} + t_{CD2}$).
4. All timing is the same for Left and Right ports. Port "A" may be either Left or Right port. Port "B" is the opposite of Port "A"

Timing Waveform with Port-to-Port Flow-Through Read[1,2,4]

5626 drw 11
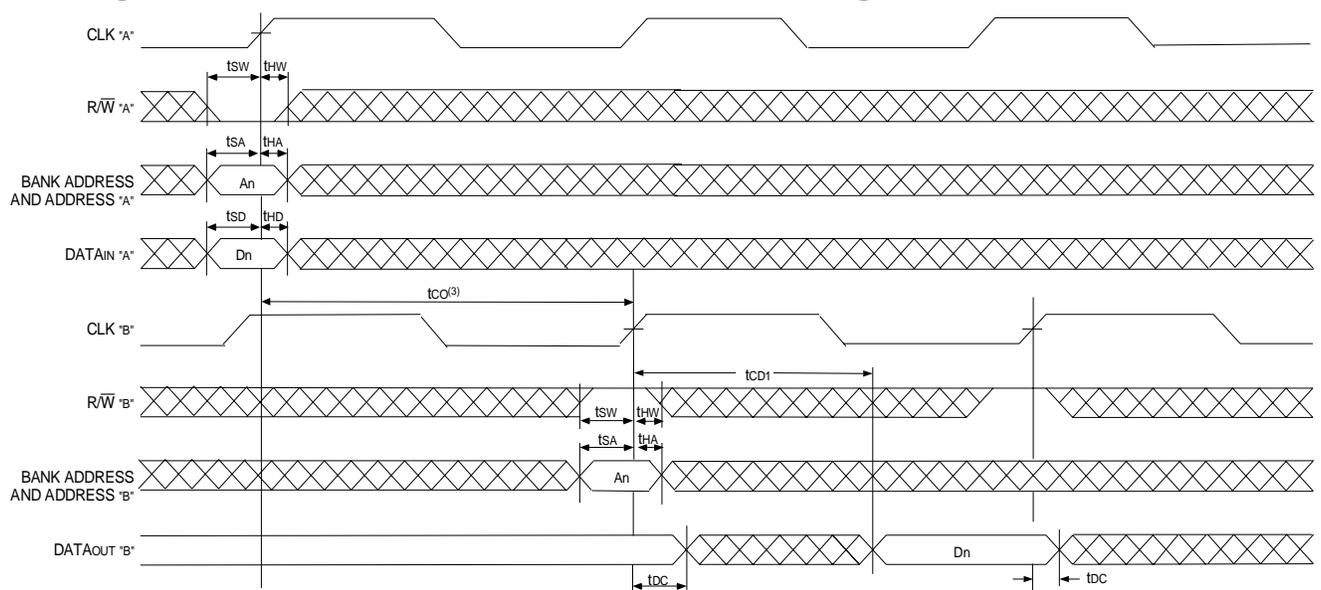
NOTES:
1. $\overline{CE}_0$, $\overline{BE}_n$, and $\overline{ADS}$ = V_{IL}; CE1, $\overline{CNTEN}$, and $\overline{REPEAT}$ = V_{IH}.
2. $\overline{OE}$ = V_{IL} for the Right Port, which is being read from. $\overline{OE}$ = V_{IH} for the Left Port, which is being written to.
3. If t_{CO} < minimum specified, then operations from both ports are INVALID. If $t_{CO} \geq$ minimum, then data from Port "B" read is available on first Port "B" clock cycle (i.e., time from write to valid read on opposite port will be $t_{CO} + t_{CD1}$).
4. All timing is the same for both left and right ports. Port "A" may be either left or right port. Port "B" is the opposite of Port "A".

Timing Waveform of Pipelined Read-to-Write-to-Read ($\overline{OE}$ = V$_{IL}$)[2]
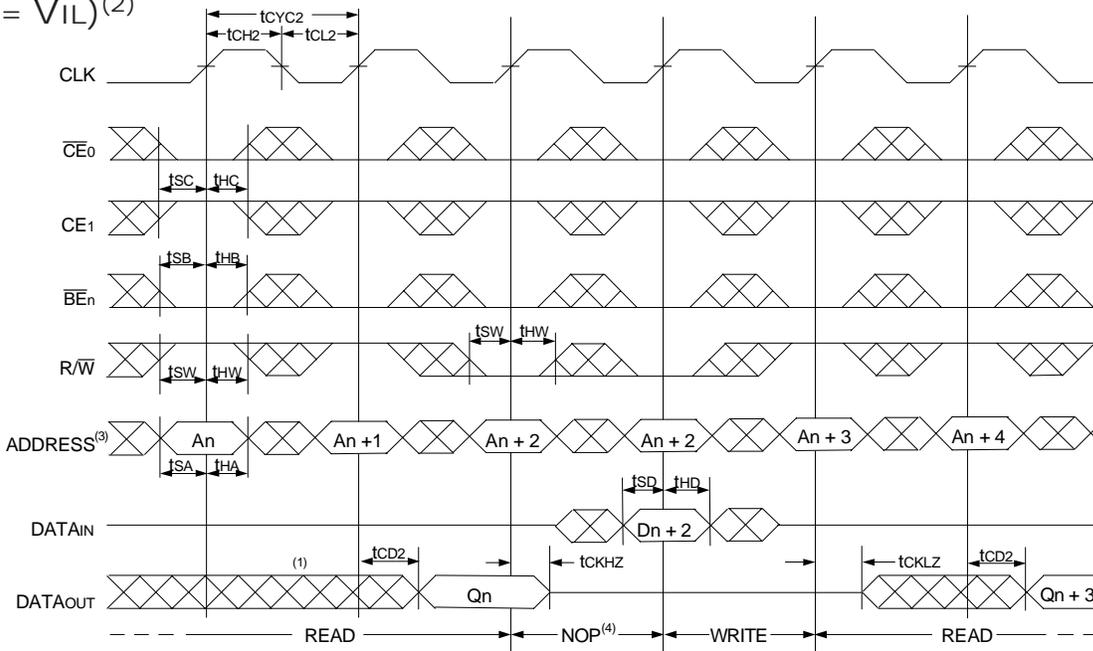

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NOTES:
1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
2. $\overline{CE}_0$, $\overline{BE}_n$, and $\overline{ADS}$ = V$_{IL}$; CE$_1$, $\overline{CNTEN}$, and $\overline{REPEAT}$ = V$_{IH}$. "NOP" is "No Operation".
3. Addresses do not have to be accessed sequentially since $\overline{ADS}$ = V$_{IL}$ constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
4. "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be re-written to guarantee data integrity.

Timing Waveform of Pipelined Read-to-Write-to-Read ($\overline{OE}$ Controlled)[2]
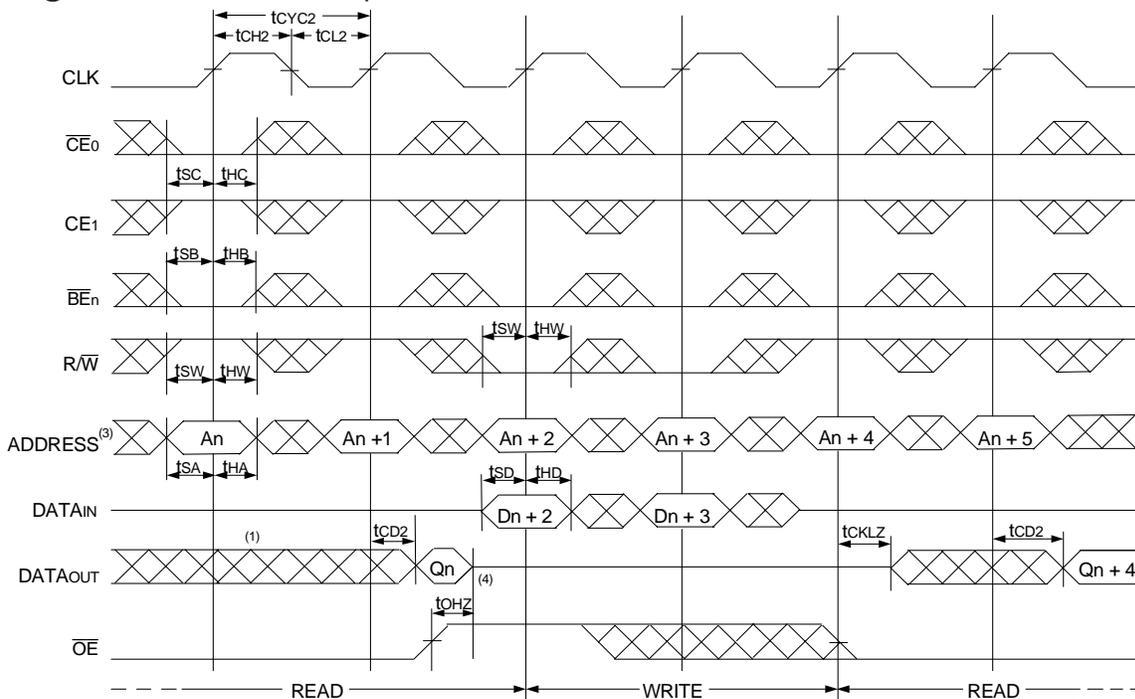
5626 drw 13

NOTES:
1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
2. $\overline{CE}_0$, $\overline{BE}_n$, and $\overline{ADS}$ = V$_{IL}$; CE$_1$, $\overline{CNTEN}$, and $\overline{REPEAT}$ = V$_{IH}$.
3. Addresses do not have to be accessed sequentially since $\overline{ADS}$ = V$_{IL}$ constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
4. This timing does not meet requirements for fastest speed grade. This waveform indicates how logically it could be done if timing so allows.

Timing Waveform of Flow-Through Read-to-Write-to-Read ($\overline{\text{OE}}$ = V$_{\text{IL}}$)$^{(2)}$
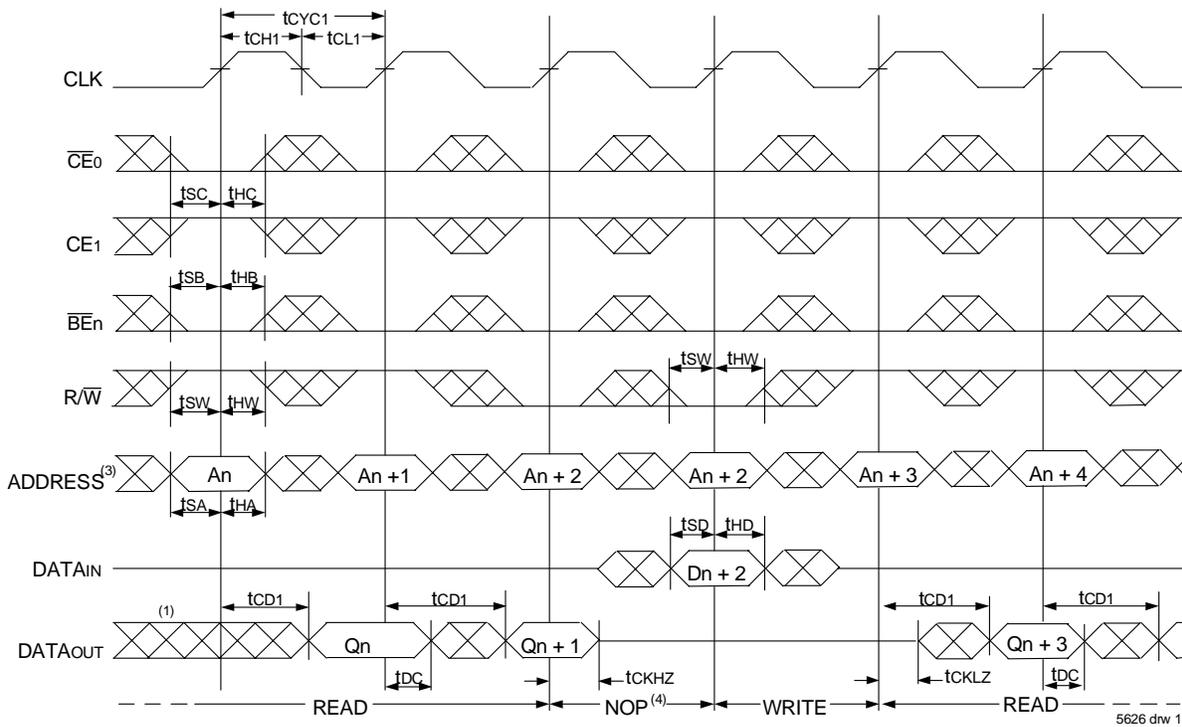
5626 drw 14

Timing Waveform of Flow-Through Read-to-Write-to-Read ($\overline{\text{OE}}$ Controlled)$^{(2)}$

5626 drw 15

NOTES:
1. Output state (High, Low, or High-impedance) is determined by the previous cycle control signals.
2. $\overline{\text{CE}}0$, $\overline{\text{BE}}n$, and $\overline{\text{ADS}}$ = V$_{\text{IL}}$; CE$_1$, $\overline{\text{CNTEN}}$, and $\overline{\text{REPEAT}}$ = V$_{\text{IH}}$.
3. Addresses do not have to be accessed sequentially since $\overline{\text{ADS}}$ = V$_{\text{IL}}$ constantly loads the address on the rising edge of the CLK; numbers are for reference use only.
4. "NOP" is "No Operation." Data in memory at the selected address may be corrupted and should be re-written to guarantee data integrity.

Timing Waveform of Pipelined Read with Address Counter Advance[1]

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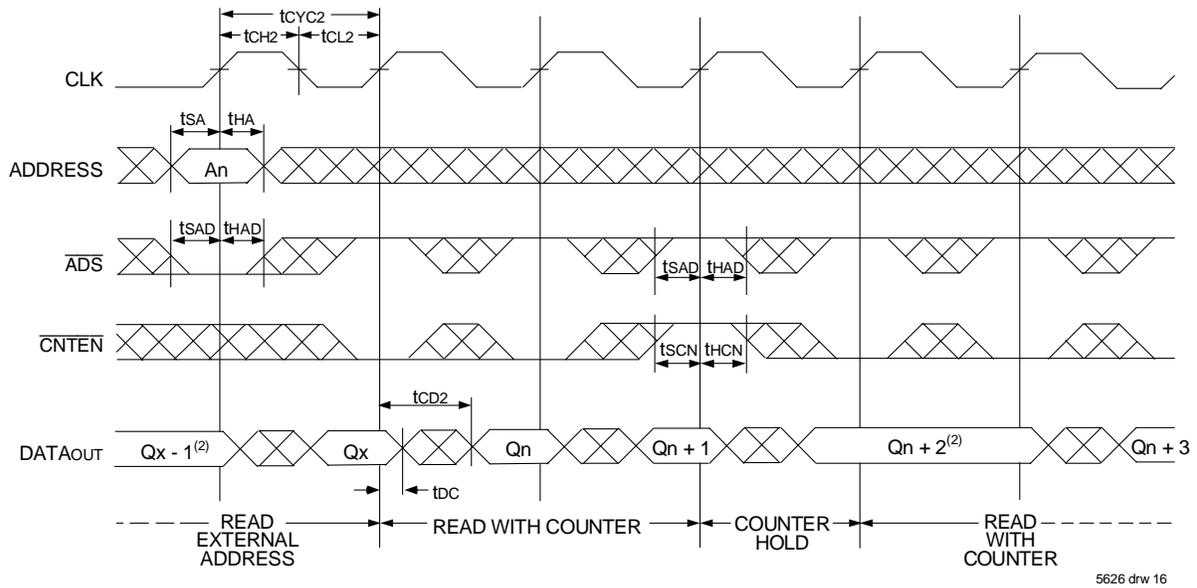
Timing Waveform of Flow-Through Read with Address Counter Advance[1]

5626 drw 17
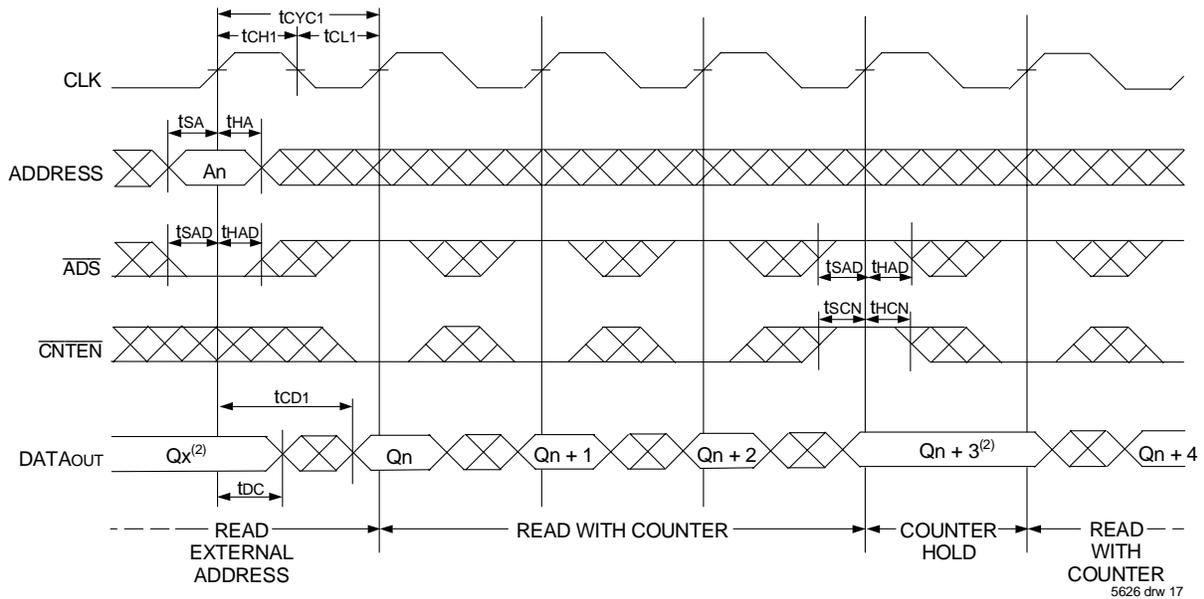
NOTES:
1. $\overline{CE0}$, $\overline{OE}$, $\overline{BEn}$ = V_{IL}; CE1, R/$\overline{W}$, and $\overline{REPEAT}$ = V_{IH}.
2. If there is no address change via $\overline{ADS}$ = V_{IL} (loading a new address) or $\overline{CNTEN}$ = V_{IL} (advancing the address), i.e. $\overline{ADS}$ = V_{IH} and $\overline{CNTEN}$ = V_{IH}, then the data output remains constant for subsequent clocks.

Timing Waveform of Write with Address Counter Advance (Flow-through or Pipelined Inputs)[1,6]

5626 drw 18
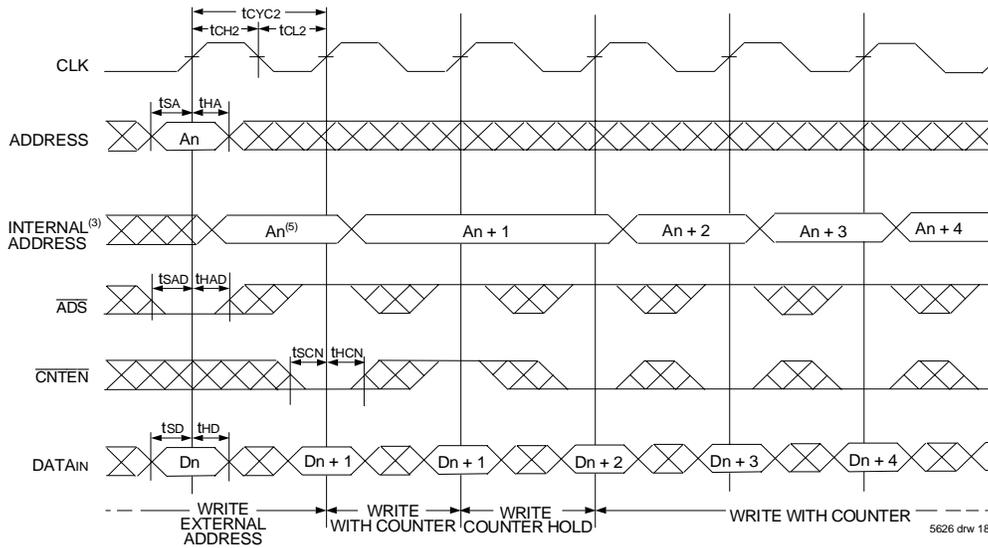
Timing Waveform of Counter Repeat for Flow Through Mode[2,6,7]

5626 drw 19
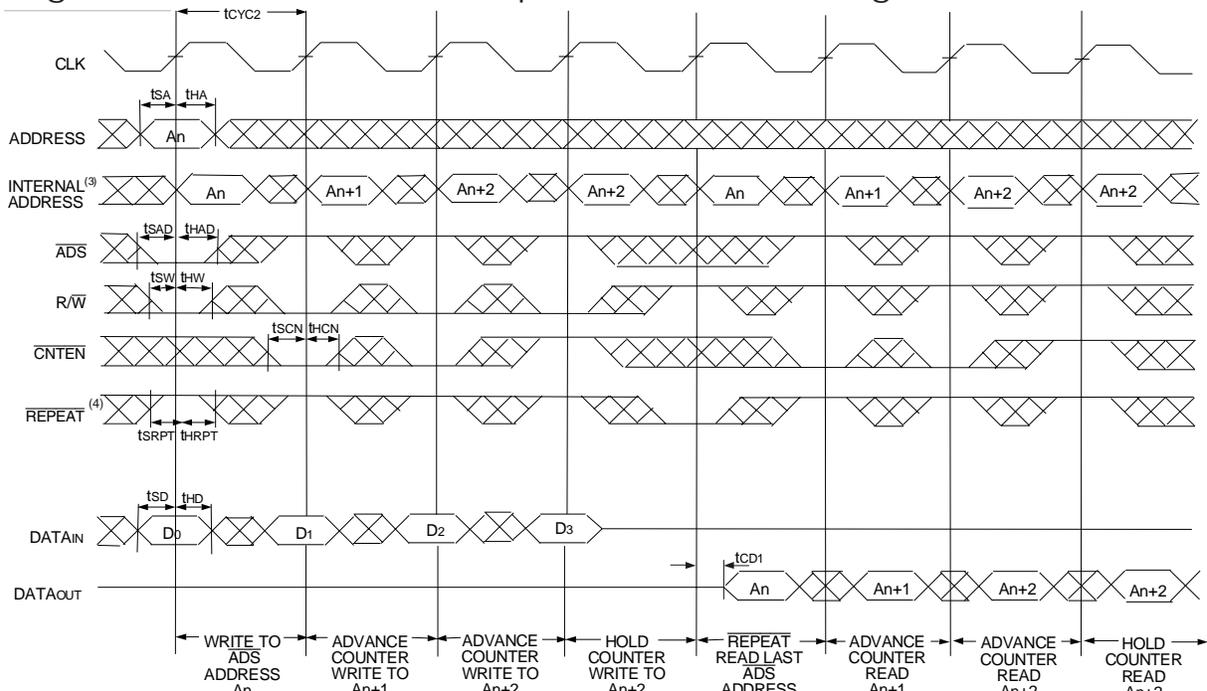
NOTES:
1. $\overline{CE_0}$, $\overline{BE_n}$, and R/$\overline{W}$ = V_{IL}; CE_1 and $\overline{REPEAT}$ = V_{IH}.
2. $\overline{CE_0}$, $\overline{BE_n}$ = V_{IL}; CE_1 = V_{IH}.
3. The "Internal Address" is equal to the "External Address" when $\overline{ADS}$ = V_{IL} and equals the counter output when $\overline{ADS}$ = V_{IH}.
4. No dead cycle exists during $\overline{REPEAT}$ operation. A READ or WRITE cycle may be coincidental with the counter $\overline{REPEAT}$ cycle: Address loaded by last valid $\overline{ADS}$ load will be accessed. For more information on $\overline{REPEAT}$ function refer to Truth Table II.
5. $\overline{CNTEN}$ = V_{IL} advances Internal Address from 'An' to 'An +1'. The transition shown indicates the time required for the counter to advance. The 'An +1'Address is written to during this cycle.
6. The counter includes bank address and internal address. The counter will advance across bank boundaries. For example, if the counter is in Bank 0, at address FFFh, and is advanced one location, it will move to address 0h in Bank 1. By the same token, the counter at FFFh in Bank 63 will advance to 0h in Bank 0.
7. For Pipelined Mode user should add 1 cycle latency for outputs as per timing waveform of read cycle for pipelined operations.

Functional Description

The IDT70V7599 is a high-speed 128Kx36 (4 Mbit) synchronous Bank-Switchable Dual-Ported SRAM organized into 64 independent 2Kx36 banks. Based on a standard SRAM core instead of a traditional true dual-port memory core, this bank-switchable device offers the benefits of increased density and lower cost-per-bit while retaining many of the features of true dual-ports. These features include simultaneous, random access to the shared array, separate clocks per port, 166 MHz operating speed, full-boundary counters, and pinouts compatible with the IDT70V3599 (128Kx36) dual-port family.

The two ports are permitted independent, simultaneous access into separate banks within the shared array. Access by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory with the shared array that is not currently being accessed by the opposite port (i.e., BA_{0L} - BA_{5L} $\neq BA_{0R}$ - BA_{5R}). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the ports within that bank may be corrupted (in the case that either or both ports are writing) or may result in invalid output (in the case that both ports are trying to read).

The IDT70V7599 provides a true synchronous Dual-Port Static RAM

interface. Registered inputs provide minimal setup and hold times on address, data and all critical control inputs.

An asynchronous output enable is provided to ease asynchronous bus interfacing. Counter enable inputs are also provided to stall the operation of the address counters for fast interleaved memory applications.

A HIGH on $\overline{CE_0}$ or a LOW on CE_1 for one clock cycle will power down the internal circuitry on each port (individually controlled) to reduce static power consumption. Dual chip enables allow easier banking of multiple IDT70V7599S for depth expansion configurations. Two cycles are required with $\overline{CE_0}$ LOW and CE_1 HIGH to read valid data on the outputs.

Depth and Width Expansion

The IDT70V7599 features dual chip enables (refer to Truth Table I) in order to facilitate rapid and simple depth expansion with no requirements for external logic. Figure 4 illustrates how to control the various chip enables in order to expand two devices in depth.

The IDT70V7599 can also be used in applications requiring expanded width, as indicated in Figure 4. Through combining the control signals, the devices can be grouped as necessary to accommodate applications needing 72-bits or wider.
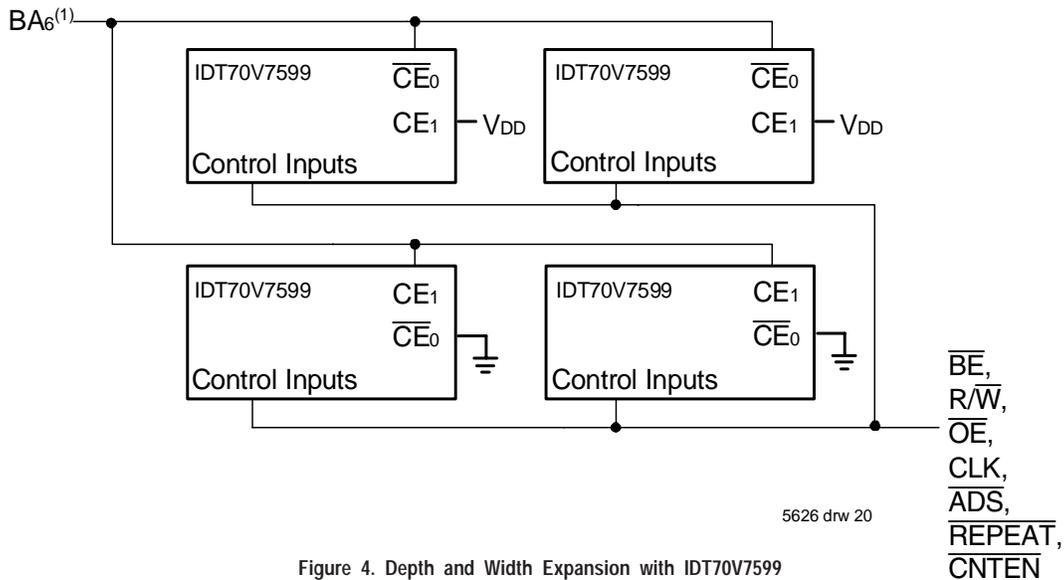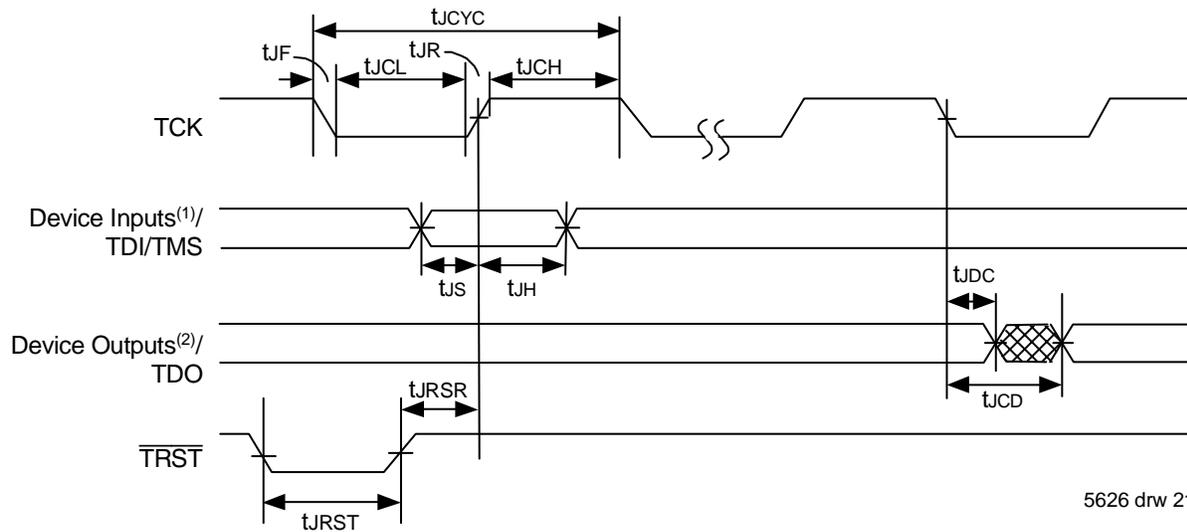

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Figure 4. Depth and Width Expansion with IDT70V7599

NOTE:
1. In the case of depth expansion, the additional address pin logically serves as an extension of the bank address. Accesses by the ports into specific banks are controlled by the bank address pins under the user's direct control: each port can access any bank of memory within the shared array that is not currently being accessed by the opposite port (i.e., BA_{0L} - BA_{6L} $\neq BA_{0R}$ - BA_{6R}). In the event that both ports try to access the same bank at the same time, neither access will be valid, and data at the two specific addresses targeted by the parts within that bank may be corrupted (in the case that either or both parts are writing) or may result in invalid output (in the case that both ports are trying to read).

JTAG Timing Specifications

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Figure 5. Standard JTAG Timing

NOTES:
1. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
2. Device outputs = All device outputs except TDO.

JTAG AC Electrical Characteristics[1,2,3,4]

Symbol	Parameter	70V7599		Units
		Min.	Max.	
t_{JCYC}	JTAG Clock Input Period	100	—	ns
t_{JCH}	JTAG Clock HIGH	40	—	ns
t_{JCL}	JTAG Clock Low	40	—	ns
t_{JR}	JTAG Clock Rise Time	—	3[1]	ns
t_{JF}	JTAG Clock Fall Time	—	3[1]	ns
t_{JRST}	JTAG Reset	50	—	ns
t_{JRSR}	JTAG Reset Recovery	50	—	ns
t_{JCD}	JTAG Data Output	—	25	ns
t_{JDC}	JTAG Data Output Hold	0	—	ns
t_{JS}	JTAG Setup	15	—	ns
t_{JH}	JTAG Hold	15	—	ns

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NOTES:
1. Guaranteed by design.
2. 30pF loading on external output signals.
3. Refer to AC Electrical Test Conditions stated earlier in this document.
4. JTAG operations occur at one speed (10MHz). The base device may run at any speed specified in this datasheet.

Identification Register Definitions

Instruction Field	Value	Description
Revision Number (31:28)	0x0	Reserved for version number
IDT Device ID (27:12)	0x308	Defines IDT part number
IDT JEDEC ID (11:1)	0x33	Allows unique identification of device vendor as IDT
ID Register Indicator Bit (Bit 0)	1	Indicates the presence of an ID register

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Scan Register Sizes

Register Name	Bit Size
Instruction (IR)	4
Bypass (BYR)	1
Identification (IDR)	32
Boundary Scan (BSR)	Note (3)

5626 tbl 14

System Interface Parameters

Instruction	Code	Description
EXTEST	0000	Forces contents of the boundary scan cells onto the device outputs[1]. Places the boundary scan register (BSR) between TDI and TDO.
BYPASS	1111	Places the bypass register (BYR) between TDI and TDO.
IDCODE	0010	Loads the ID register (IDR) with the vendor ID code and places the register between TDI and TDO.
HIGHZ	0100	Places the bypass register (BYR) between TDI and TDO. Forces all device output drivers to a High-Z state.
CLAMP	0011	Uses BYR. Forces contents of the boundary scan cells onto the device outputs. Places the bypass register (BYR) between TDI and TDO.
SAMPLE/PRELOAD	0001	Places the boundary scan register (BSR) between TDI and TDO. SAMPLE allows data from device inputs[2] and outputs[1] to be captured in the boundary scan cells and shifted serially through TDO. PRELOAD allows data to be input serially into the boundary scan cells via the TDI.
RESERVED	All other codes	Several combinations are reserved. Do not use codes other than those identified above.

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NOTES:
1. Device outputs = All device outputs except TDO.
2. Device inputs = All device inputs except TDI, TMS, TRST, and TCK.
3. The Boundary Scan Descriptive Language (BSDL) file for this device is available on the IDT website (www.idt.com), or by contacting your local IDT sales representative.

Ordering Information

```
XXXXX      A      999      A      A
```

| Device Type | Power | Speed | Package | Process/Temperature Range |

| | | | | Blank | Commercial (0°C to +70°C) |
| | | | | I | Industrial (-40°C to +85°C) |

			BF	208-pin fpBGA (BF-208)
			DR	208-pin PQFP (DR-208)
			BC	256-pin BGA (BC-256)

		200	Commercial Only[1]
		166	Commercial & Industrial[2]	Speed in Megahertz
		133	Commercial & Industrial

| | S | Standard Power |

70V7599 4Mbit (128K x 36-Bit) Synchronous Bank-Switchable Dual-Port RAM

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NOTES:
1. Available in BC-256 package only.
2. Industrial Temperature at 166Mhz not available in BF-208 package.

Datasheet Document History: